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**Figure 1.3** Courtesy of Sandia National Laboratory.

**Figure 1.4** McKernan, S., MGN & CBC.

**Figure 1.5** Data from Kingery, W.D., Bowen, H.K., and Uhlmann, D.R. (1976) *Introduction to Ceramics* 2<sup>nd</sup> Ed., p. 1008.

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**Table 1.3** From the NIST Reference on Constants, Units, and Uncertainty ([www.physics.nist.gov](http://www.physics.nist.gov)).

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**Figure 2.9** Data from Ashby, M.F. and Jones, D.R.H. (1986) *Engineering Materials 2*, Pergamon Press, Oxford, p. 192.

**Figure 2.10** Data from Ashby, M.F. and Jones, D.R.H. (1986) *Engineering Materials 2*, Pergamon Press, Oxford, p. 192.

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## Chapter 9

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**Table 9.8** The pyrometric cone equivalent test is described in ASTM Standard C24-56.

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**Figure 10.33** Altay, A. & CBC.

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**Figure 21.5** Redrawn after schematics on the Edward J. Orton Jr. Ceramic Foundation site (ANS-800 and RSV-1600); see [www.ortonceramic.com/instruments](http://www.ortonceramic.com/instruments) (and don't miss the Orton cones video).

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**Figure 27.3** Courtesy of Richard E. Mistler, Inc., Yardley, PA, USA.

**Figure 27.4** Courtesy of Keko Equipment (Slovenia) and Haiku Tech, Inc. (USA).

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**Table 37.4** Data from Schoenung, J.M. (1991) “Analysis of the economics of silicon nitride powder production,” *Am. Ceram. Soc. Bull.* 70, 114.

**Table 37.5** Data from Business Communications Co., Inc. Reprinted in *Am. Ceram. Soc. Bull.*, March 2002, 71, 34.

**Table 37.6** Data from *Advanced Ceramics Technology Roadmap—Charting Our Course*. December 2000. Sponsored by United States Advanced Ceramic Association and the U.S. Department of Energy, p. 16.

**Table 37.7** Data compiled by Hummel, R.E. (1998) *Understanding Materials Science*, Springer, New York, p. 372.

**Table 37.8** Data compiled by Hummel, R.E. (1998) *Understanding Materials Science*, Springer, New York, p. 373.

**Table 37.9** Data from Siikamäki, R. and Hupa, L. (2001) “Utilization of EOL CRT-glass as a glaze raw material,” in: *Recycling and Reuse of Glass Cullet*, Dhir, R.K., Limbachiya, M.C., and Dyer, T.D., Eds., Thomas Telford, London, p. 136.